

Notice of References Cited			Application/Control No.	Applicant(s)/Patent Under Reexamination	
			10/816,150	ELFADEL, IBRAHIM M.	
Examiner Shambhavi Patel			Art Unit 2128	Page 1 of 1	

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*	B	US-6,188,974	02-2001	Cullum et al.	703/14
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NON-PATENT DOCUMENTS

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*	V	Jaijeet Royschowdhury. 'Automated Macromodel Generation for Electronic Systems'. August 2003.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.